PCN Number:		20180626001.1							F	PCN Da	ate:	June 28, 2018			
Title: Qualifica			ation of Carsem as additional Assembly and Bump Site for Select Devices												
Customer Conta			ct: P	, ,											
Proposed 1 st Shi							_	Estimated 9			Date provided at sample request				
Cha	ange	Туре:			<u> </u>			7. Trailed							
					Design				Wafer Bump Site						
	Asse	mbly Pro	cess				Data Sheet				Wafer Bump Material				
\boxtimes	Asse	mbly Ma	terials				Part number change				Wafer Bump Process				
	Mech	nanical S	pecifica	tion			Test Site				Wafer Fab Site				
	Pack	ing/Ship	oing/La	belir	ng		Test Process				Wafer Fab Materials				
											Wafer Fab Process				
PCN Details															
Des	script	ion of C	hange:	•											
Texas Instruments is pleased to anr Bump Site for select devices shown are noted below: Mount compound					below in the product affected sec										
			compound							SID#441086					
	,														
Rea	son	for Chan	ige:												
Con	tinuit	y of supp	ly.												
Ant	icipa	ted imp	act on	For	m, Fit,	Fu	nction,	Quality or Relia	abili	ity	(positi	ive /	negative):		
Nor	ne														
Ant	ticipa	ted imp	act on	Mat	erial D	ec	laration	1							
Material Declaration pro			terial Declarations or Product Content reports are driven from oduction data and will be available following the production ease. Upon production release the revised reports can be tained from the TI Eco-Info website. There is no impact to the sterial meeting current regulatory compliance requirements with s PCN change.												
Changes to product identification resulting from this PCN:															
Assembly Site Information:															
•		mbly	bly Site Origin (22L)			Assembly Country C	(21	L)	Ass	sembly City					
Clark AT			QAB				PHL			An	Angeles City, Pampang				
Carsem CSZ					CHN				Jiangsu						
San	Sample product shipping label (not actual product label)														

TEXAS INSTRUMENTS

MADE IN: Malaysia 2DC: 2Q: MSL 2 /260C/1 YEAR SEAL DT

MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 5A (L)T0:1750

(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2

(P) (2P) REV: (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (33L) ACO: MYS

Product Affected

TLC59581RTQR TLC59581RTQT TLC59582RTQR TLC59582RTQT



TI Information Selective Disclosure

Qualification Report

TLC59581RTQ Product Off-load Qualification/Assembled in 56ld QFN (RTQ) at Carsem Approve Date 12-June-2018

Product Attributes

Attributes	Qual Device: TLC59581RTQR	QBS Product Reference: SN015120ARTQR	QBS Package Reference: TPS650240RHBR	QBS Package Reference: SNA1010017RSAR	QBS Package Reference: TPS51123RGER	
Assembly Site	CARZ	CARZ	CARZ	CARZ	CARZ	
Package Family	VQFN	VQFN	VQFN	VQFN	VQFN	
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	
Wafer Fab Supplier	RFAB	RFAB	FR-BIP-1	MH8	DL-LIN	
Wafer Process	LBC7	LBC7	3370A12X3	LBC7	LBC4	

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TLC59581RTQR	QBS Product Reference: SN015120ARTQR	QBS Package Reference: TPS650240RHBR	QBS Package Reference: SNA1010017RSAR	QBS Package Reference: TPS51123RGER
AC	Autoclave 121C	96 Hours	-	- 3/231/0		3/231/0	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters 1/Pass		1/Pass	-	1/Pass	1/Pass
HAST	Biased HAST, 110C/85%RH	264 Hours	-	3/231/0	-	-	-
HBM	ESD - HBM	4000 V	-	-	-	-	-
HBM	ESD - HBM	1000 V	-	-	-	-	-
CDM	ESD - CDM	1500 V	-	-	-	-	-
CDM	ESD - CDM	250 V	-	-	=	-	-
HTOL	Life Test, 125C	1000 Hours	-	-	-	-	3/112/0
HTOL	Life Test, 135C	635 Hours	-	-	-	-	-
HTSL	High Temp. Storage Bake, 150C	1000 Hours	-	3/231/0	-	-	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/231/0	3/231/0	3/231/0
LU	Latch-up	(per JESD78)	-	-	-	-	-
MQ	Manufacturing (Assembly)	Per Mfg Site Specification	-	3/Pass	3/Pass	3/Pass	3/Pass
PD	Physical Dimensions	-	-	=	=	-	-
SA	Salt Atmosphere	-	-	-	-	-	3/66/0
SD	Solderability	8 Hours Steam Age	-	-	=	-	3/66/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	3/231/0	3/231/0	3/231/0
TS	Thermal Shock -65/150C	500 Cycles	-	-	-	-	-
UHAST	Unbiased HAST, 110C/85%RH	264 Hours	-	3/231/0	-	-	-
WBP	Bond Pull	Wires	-	-	-	-	-
WBS	Bond Shear	Wires	-	-	-	-	-

WiteS | Bond Shear | WireS | -Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
-The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
-The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
-The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
-Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

⁻ QBS: Qual By Similarity - Qual Device TLC59581RTQR is qualified at LEVEL3-260C

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com